

Notice of References Cited	Application/Control No. 10/550,117		Applicant(s)/Patent Under Reexamination SALMON, NEIL ANTHONY	
	Examiner Christopher P. Rivard		Art Unit 4154	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,512,741	04-1996	Levaillant et al.	250/203.3
*	B	US-4,791,427	12-1988	Raber et al.	343/754
*	C	US-5,047,783	09-1991	Hugenin, G. Richard	342/179
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 2066945 A1	08-2002	World Intellect	SALMON, NEIL ANTHONY	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Blommel, et al: "The Effects of Microscan Operation on Staring Infrared Sensor Imagery," SPIE Infrared Technology XVII (1991), Volume 1540, pages 653-664
	V	Marshall, "Risley Prism Scan Patterns," Proceedings of SPIE (July 1999), Volume 3787, pages 74-86
	W	English Machine Translation of EP 179687 A1
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.